

• General Description

The CH100P04D combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

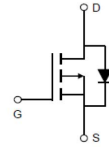
• Features

- Advance high cell density Trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

• Application

- MB/VGA Vcore
- SMPS 2nd Synchronous Rectifier
- POL application
- BLDC Motor driver

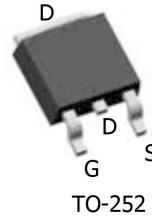
• Product Summary



$V_{DS} = -40V$

$R_{DS(ON)} < 6 m\Omega$

$I_D = -100A$



TO-252

• Ordering Information:

Part NO.	CH100P04D
Marking	CH100P04D
Packing Information	REEL TAPE
Basic ordering unit (pcs)	2500

• Absolute Maximum Ratings ($T_c = 25^\circ C$)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	-100	A
	$I_D @ T_C = 75^\circ C$	-80	A
	$I_D @ T_C = 100^\circ C$	-70	A
Pulsed Drain Current ①	I_{DM}	-396	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	107	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	4.5	W
Operating Junction Temperature	T_J	-55 to 175	$^\circ C$
Storage Temperature	T_{STG}	-55 to 175	$^\circ C$
Single Pulse Avalanche Energy @ $L = 0.1mH$	E_{AS}	576	mJ

•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R_{thJC}	-	-	1.4	$^{\circ}C/W$
Thermal resistance, junction - ambient	R_{thJA}	-	-	48	$^{\circ}C/W$
Soldering temperature, wavesoldering for 10s	T_{solder}	-	-	265	$^{\circ}C$

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=-250\mu A$	-40			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.0	-1.7	-2.5	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=-40V, V_{GS}=0V$			-1.0	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=-10V, I_D=-20A$		4.9	6.0	m Ω
		$V_{GS}=-4.5V, I_D=-20A$		6.5	8.3	m Ω
Forward Transconductance	g_{FS}	$V_{DS}=-5V, I_D=-20A$		59		S

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C_{iss}	$V_{DS}=-20V$ $V_{GS}=-0V$ $f=1MHz$	-	6638	-	pF
Output capacitance	C_{oss}		-	545	-	
Reverse transfer capacitance	C_{rss}		-	345	-	

•Gate Charge characteristics($T_a=25^{\circ}C$)

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q_g	$V_{DD}=-20V$ $I_D=-20A$ $V_{GS}=-10V$	-	118	-	nC
Gate - Source charge	Q_{gs}		-	13	-	
Gate - Drain charge	Q_{gd}		-	22	-	

Note: ① Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;

② Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;

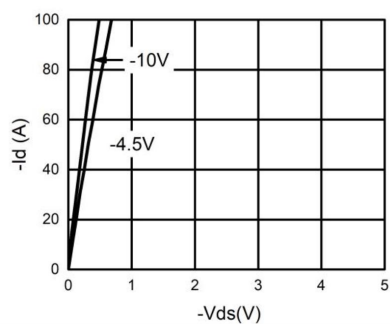
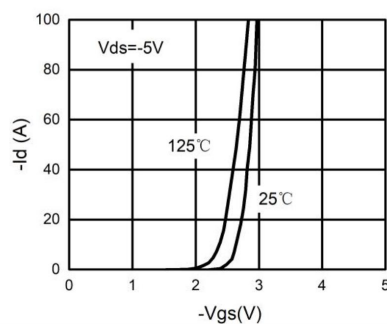
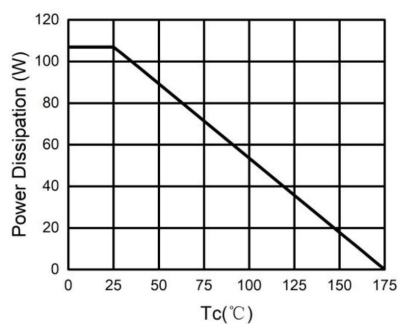
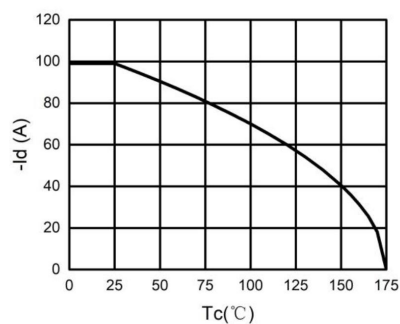
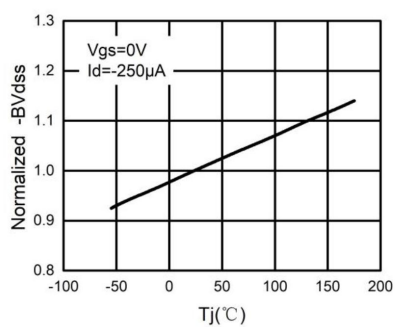
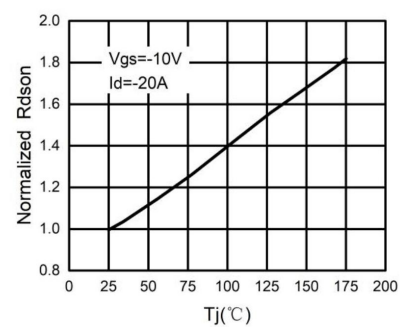
Figure 1. Output Characteristics

Figure 2. Transfer Characteristics

Figure 3. Power Dissipation

Figure 4. Drain Current

Figure 5. BV_{DS} vs Junction Temperature

Figure 6. $R_{DS(ON)}$ vs Junction Temperature


Figure 7. Gate Charge Waveforms

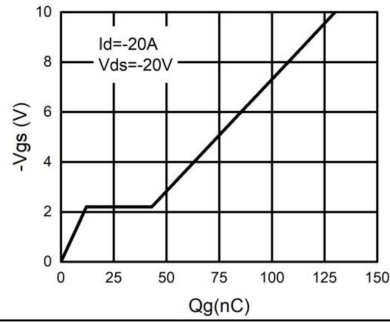


Figure 8. Capacitance

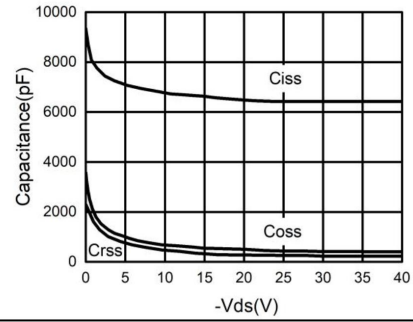


Figure 9. Body-Diode Characteristics

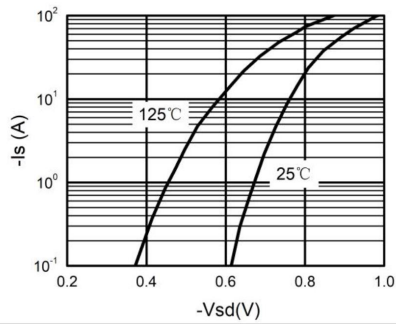
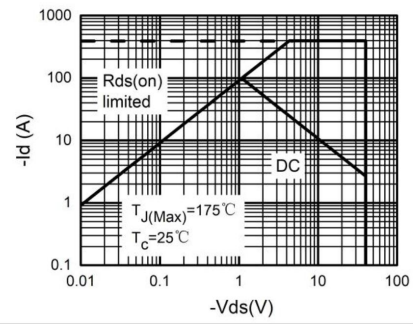
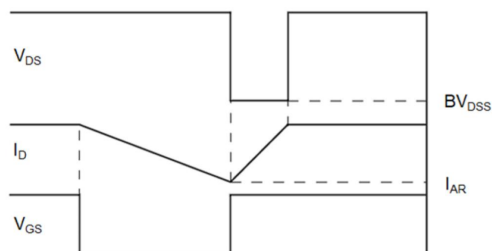
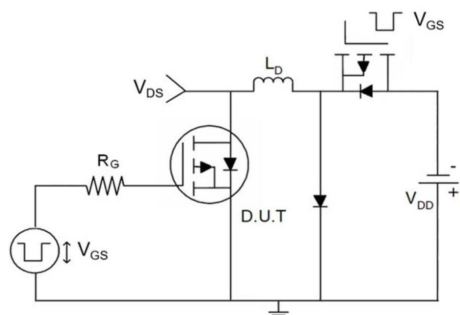


Figure 10. Maximum Safe Operating Area

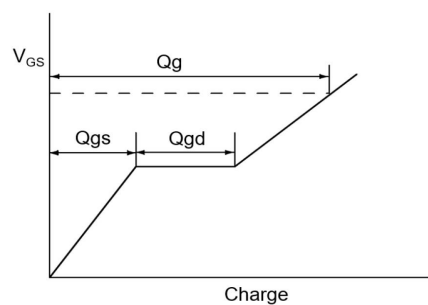
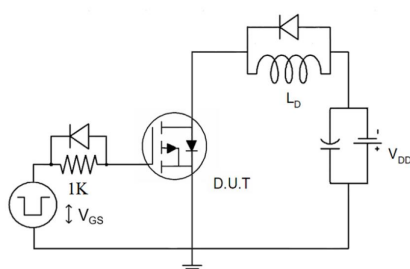


Test Circuit

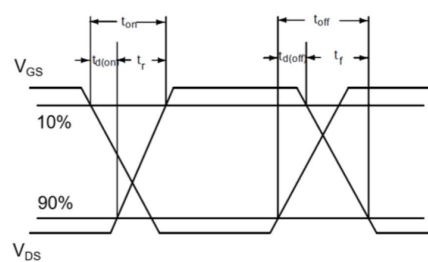
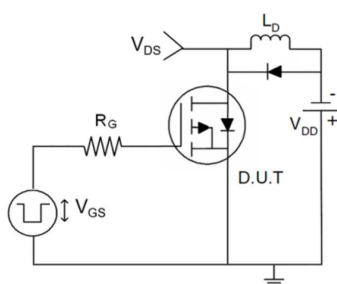
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



• Dimensions (TO-252)

Unit: mm

SYMBOL	min	max	SYMBOL	min	max
A	2.10	2.50	B	0.85	1.25
b	0.50	0.80	b1	0.50	0.90
b2	0.45	0.70	C	0.45	0.70
D	6.30	6.75	D1	5.10	5.50
E	5.30	6.30	e1	2.25	2.35
L1	9.20	10.60	e2	4.45	4.75
L2	0.90	1.75	L3	0.60	1.10
K	0.00	0.23			

